

US 6,366,002 B1

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component, said substrate has Euler angles of approximately (0°, 125°–147°, 0°±5°), and said normalized film thickness H/λ is within the range of approximately 0.003 to 0.05.

9. A surface acoustic wave device according to claim 1, wherein said interdigital transducer includes Zn as a major component, said substrate has Euler angles of approximately (0°, 125°–138°, 0°±5°), and said normalized film thickness H/λ is within the range of approximately 0.003 to 0.05.

10. A surface acoustic wave device according to claim 1, wherein said interdigital transducer includes W as a major component, said substrate has Euler angles of approximately (0°, 125°–138°, 0°±5°), and said normalized film thickness H/λ is within the range of approximately 0.002 to 0.05.

11. A communication device including the surface acoustic wave device according to claim 1.

12. A communication device including the surface acoustic wave device according to claim 2.

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13. A communication device including the surface acoustic wave device according to claim 3.

14. A communication device including the surface acoustic wave device according to claim 4.

15. A communication device including the surface acoustic wave device according to claim 5.

16. A communication device including the surface acoustic wave device according to claim 6.

17. A communication device including the surface acoustic wave device according to claim 7.

18. A communication device including the surface acoustic wave device according to claim 8.

19. A communication device including the surface acoustic wave device according to claim 9.

15 20. A communication device including the surface acoustic wave device according to claim 10.

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